

L Number	Hits	Search Text	DB	Time stamp
-	967	(BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 15:01
-	281	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 14:54
-	365	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ti. ((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 15:05
-	300	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/19 15:07
-	163	((BIST BISR "built in self test" "built-in self-test" built-in-self-test) with (memory RAM ROM SRAM DRAM CAM FLASH EPROM EEPROM DROM cache)) and ((ATE "automatic test equipment" tester) and (flip-flop latch selector "flip flop" flipflop "shift register")) and (buffer and control\$3 and (selector flip-flop latch selector "flip flop" flipflop "shift register"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/21 10:40
-	2	5235600.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/21 10:45